

U.S. UTILITY Patent Application

O.I.P.E.

PATENT DATE

APPLICATION NO. 09/932754	CONT/PRIOR D	CLASS 408 324	SUBCLASS 782.000	ART UNIT 2820 2820	EXAMINER Hollington
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Real-time in-line testing of semiconductor wafers

PTO-2040
12/99

ISSUING CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				

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	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
				NOTICE OF ALLOWANCE MAILED _____ (Assistant Examiner) _____ (Date)	
				ISSUE FEE Amount Due _____ Date Paid _____	
				ISSUE BATCH NUMBER _____ (Legal Instruments Examiner) _____ (Date)	

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